PD - 95053A

International Rectifier

Advanced Process Technology

- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

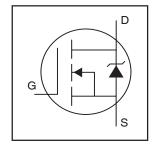
Description

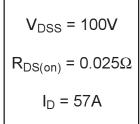
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

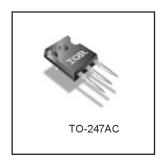
The TO-247AC package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-247AC contribute to its wide acceptance throughout the industry.

IRFP3710PbF

HEXFET® Power MOSFET







Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	57	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	40	Α
I _{DM}	Pulsed Drain Current ①	180	
P _D @T _C = 25°C	Power Dissipation	200	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy®	530	mJ
I _{AR}	Avalanche Current①	28	Α
E _{AR}	Repetitive Avalanche Energy①	20	mJ
dv/dt	Peak Diode Recovery dv/dt ③	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		0.75	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

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Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	100			V	$V_{GS} = 0V, I_D = 250 \mu A$
Breakdown Voltage Temp. Coefficient		0.12		V/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance			0.025	Ω	V _{GS} = 10V, I _D = 28A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$
Forward Transconductance	20			S	V _{DS} = 25V, I _D = 28A
Drain-to-Source Leakage Current			25	μA	V _{DS} = 100V, V _{GS} = 0V
			250		$V_{DS} = 80V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
Gate-to-Source Forward Leakage			100	n A	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	IIA	V _{GS} = -20V
Total Gate Charge			190		I _D = 28A
Gate-to-Source Charge			26	nC	V _{DS} = 80V
Gate-to-Drain ("Miller") Charge			82		V _{GS} = 10V, See Fig. 6 and 13 ⊕
Turn-On Delay Time		14			V _{DD} = 50V
RiseTime		59		_	I _D = 28A
Turn-Off Delay Time		58		ns	$R_G = 2.5\Omega$
Fall Time		48			R_D = 1.7 Ω , See Fig. 10 \oplus
Internal Drain Inductance		4.5		nl l	Between lead,
					6mm (0.25in.)
Internal Source Inductance		7.5		7 ""	from package
					and center of die contact
Input Capacitance		3000			V _{GS} = 0V
Output Capacitance		640		pF	V _{DS} = 25V
Reverse Transfer Capacitance		330			f = 1.0MHz, See Fig. 5
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage 100 — Breakdown Voltage Temp. Coefficient — 0.12 Static Drain-to-Source On-Resistance — — Gate Threshold Voltage 2.0 — Forward Transconductance 20 — Drain-to-Source Leakage Current — — Gate-to-Source Forward Leakage — — Gate-to-Source Reverse Leakage — — Total Gate Charge — — Gate-to-Source Charge — — Gate-to-Drain ("Miller") Charge — — Turn-On Delay Time — 14 Rise Time — 59 Turn-Off Delay Time — 48 Internal Drain Inductance — 4.5 Internal Source Inductance — 7.5 Input Capacitance — 640	Drain-to-Source Breakdown Voltage 100 — — Breakdown Voltage Temp. Coefficient — 0.12 — Static Drain-to-Source On-Resistance — 0.025 Gate Threshold Voltage 2.0 — 4.0 Forward Transconductance 20 — — Drain-to-Source Leakage Current — — 25 Gate-to-Source Forward Leakage — — 100 Gate-to-Source Reverse Leakage — — 100 Total Gate Charge — — 190 Gate-to-Source Charge — — 26 Gate-to-Drain ("Miller") Charge — 82 Turn-On Delay Time — 14 — Rise Time — 59 — Turn-Off Delay Time — 58 — Fall Time — 4.5 — Internal Drain Inductance — 7.5 — Internal Capacitance — 640 —	Drain-to-Source Breakdown Voltage 100 — — V Breakdown Voltage Temp. Coefficient — 0.12 — V°C Static Drain-to-Source On-Resistance — — 0.025 Ω Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 20 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Total Gate Charge — — 190 nC Gate-to-Source Charge — — 26 nC Gate-to-Drain ("Miller") Charge — 82 nC Turn-On Delay Time — 59 — Rise Time — 58 — Tall Time — 48 — Internal Drain Inductance — 7.5 — Input Capacita

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions							
Is	Continuous Source Current			57		MOSFET symbol							
	(Body Diode)	ode)	57	A	showing the								
I _{SM}	Pulsed Source Current			100	400	400	400	400	100	100	400		integral reverse ^G
	(Body Diode) ①	_	180		p-n junction diode.								
V_{SD}	Diode Forward Voltage			1.3	V	$T_J = 25$ °C, $I_S = 28A$, $V_{GS} = 0V$ ④							
t _{rr}	Reverse Recovery Time		210	320	ns	$T_J = 25^{\circ}C, I_F = 28A$							
Q _{rr}	Reverse RecoveryCharge		1.7	2.6	μC	di/dt = 100A/µs ⊕							
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)											

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Starting T_J = 25°C, L = 1.4mH R_G = 25 Ω , I_{AS} = 28A. (See Figure 12)
- $\label{eq:loss_def} \begin{tabular}{l} \Im & I_{SD} \leq 28A, \ di/dt \leq 460A/\mu s, \ V_{DD} \leq V_{(BR)DSS}, \\ & T_{J} \leq 175^{\circ}C \end{tabular}$
- 4 Pulse width \leq 300 μ s; duty cycle \leq 2%.

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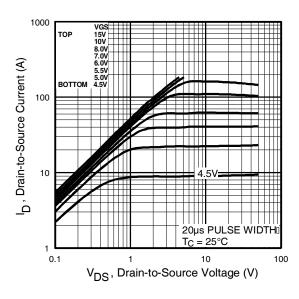


Fig 1. Typical Output Characteristics

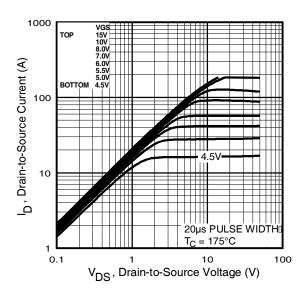


Fig 2. Typical Output Characteristics

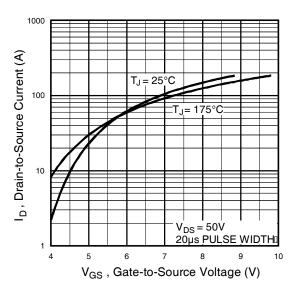


Fig 3. Typical Transfer Characteristics

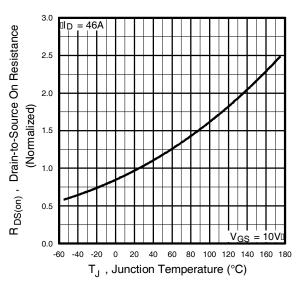


Fig 4. Normalized On-Resistance Vs. Temperature

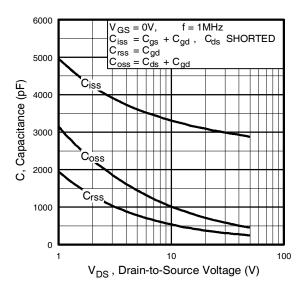


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

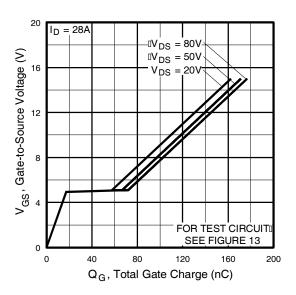


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

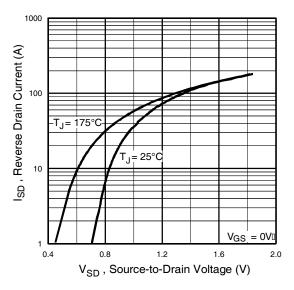


Fig 7. Typical Source-Drain Diode Forward Voltage

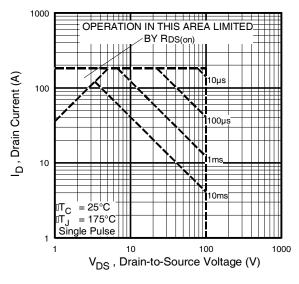


Fig 8. Maximum Safe Operating Area

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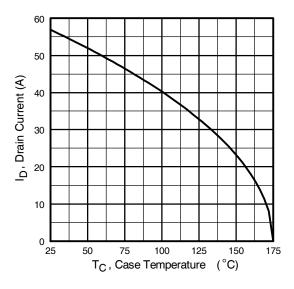


Fig 9. Maximum Drain Current Vs.
Case Temperature

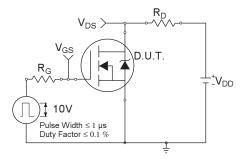


Fig 10a. Switching Time Test Circuit

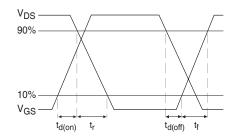


Fig 10b. Switching Time Waveforms

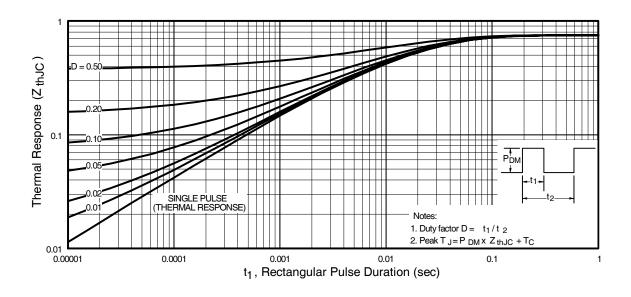


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

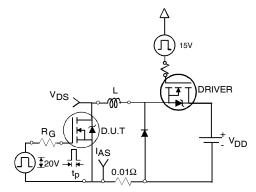


Fig 12a. Unclamped Inductive Test Circuit

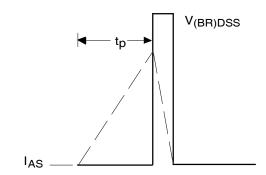


Fig 12b. Unclamped Inductive Waveforms

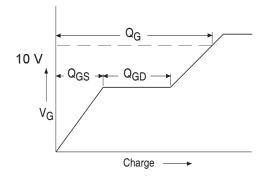


Fig 13a. Basic Gate Charge Waveform

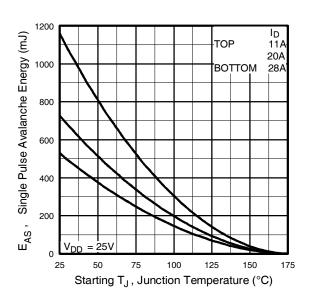


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

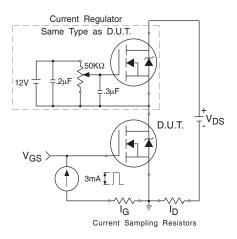
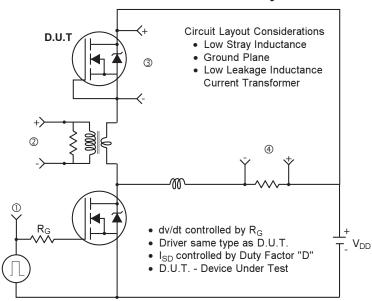
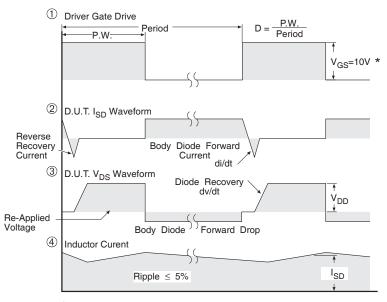


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit





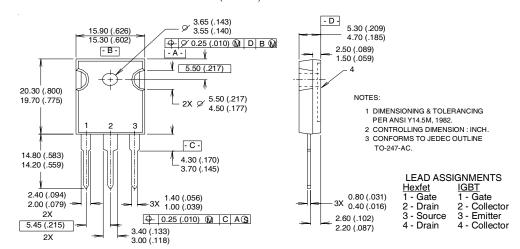
* V_{GS} = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

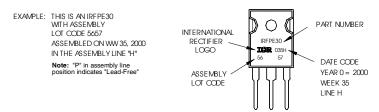
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TO-247AC Package Outline

Dimensions are shown in millimeters (inches)



TO-247AC Part Marking Information



Data and specifications subject to change without notice.



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Note: For the most current drawings please refer to the IR website at: http://www.irf.com/package/

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